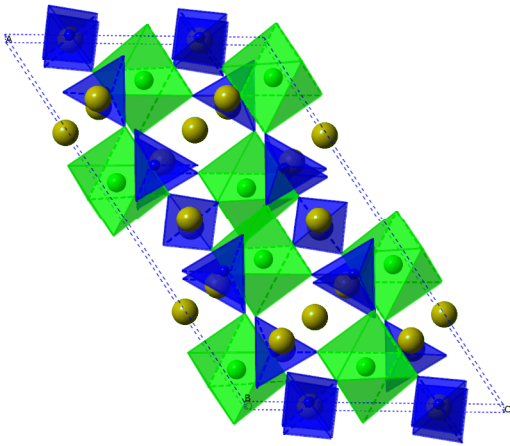


Sodium-Ion Conductivity and Scaling Effects in NaSICon Thin Films Prepared Via Chemical Solution Deposition

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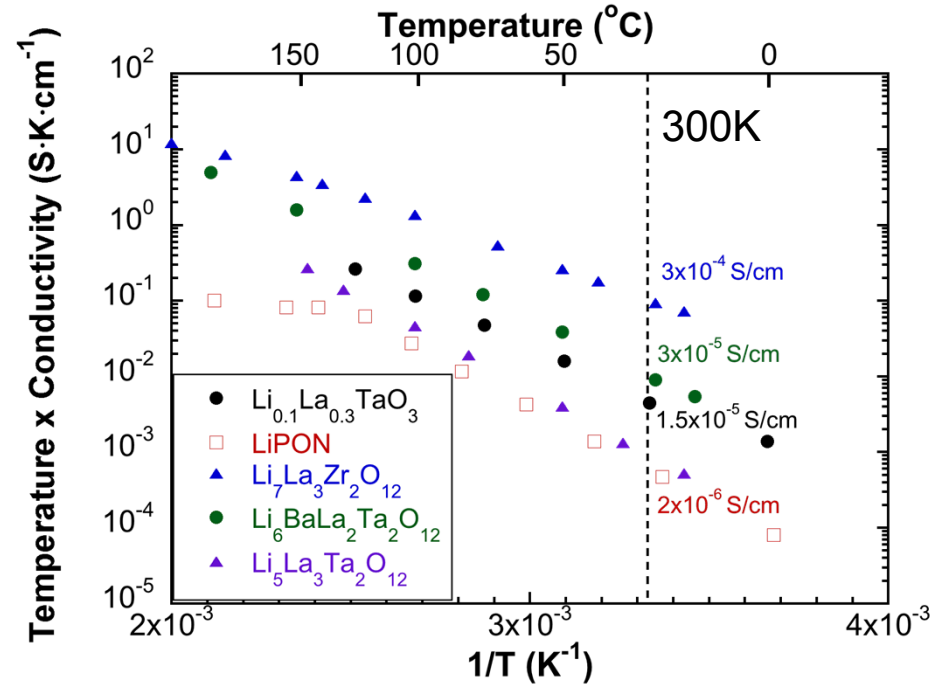
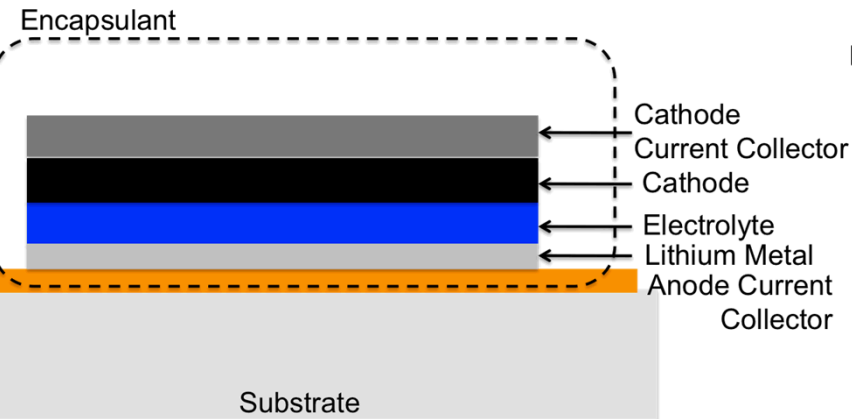
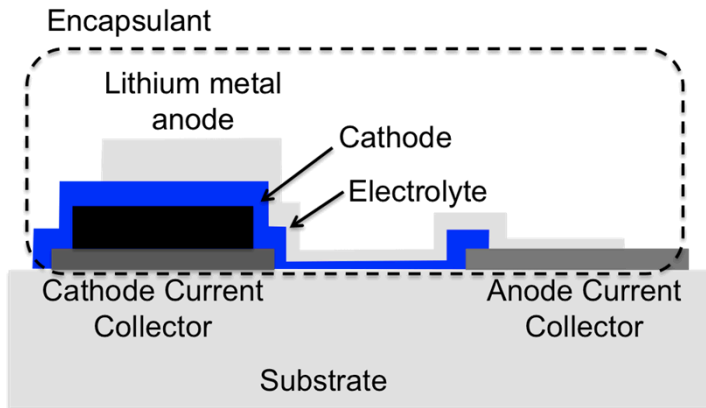
*Exceptional
service
in the
national
interest*



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Thin Film Ion Batteries

“Oak-Ridge Cell”



■ LiPON is by far the most utilized electrolyte

- Chemically stable
- High electrical resistivity

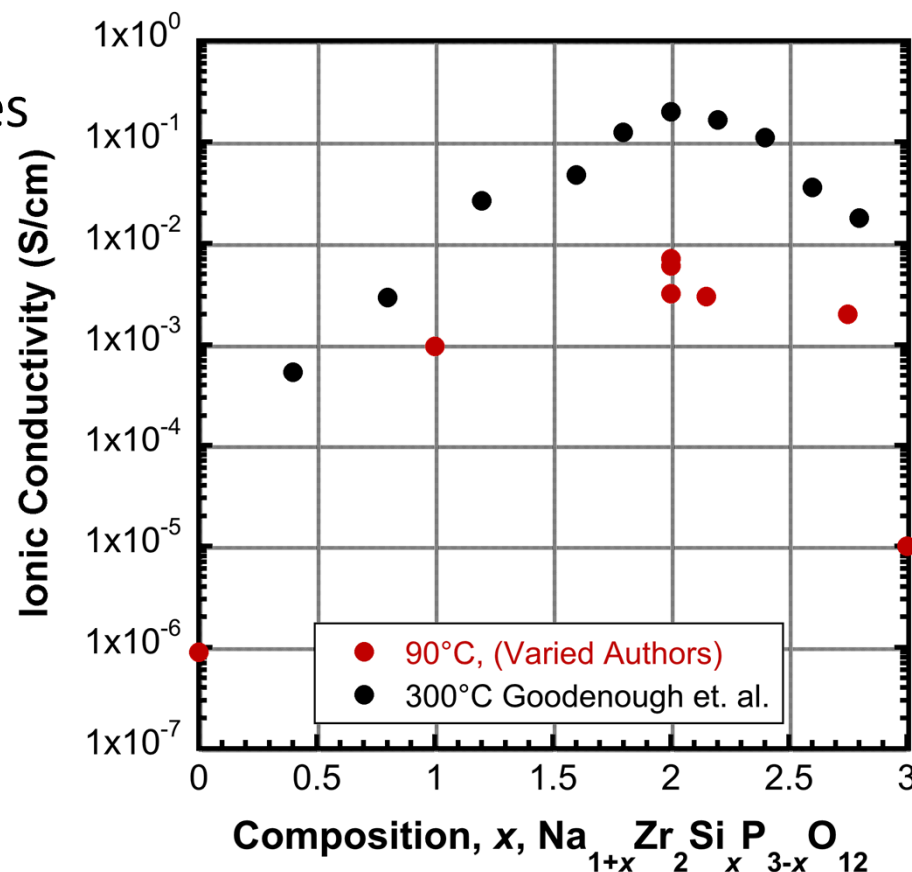
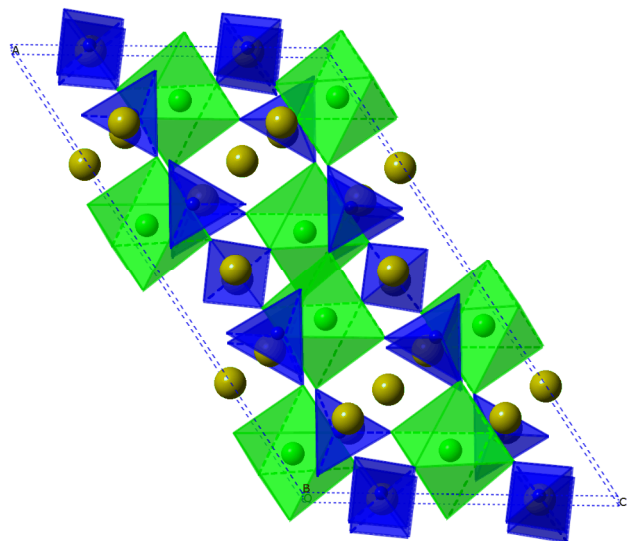
■ Ionic conductivity is modest and can limit power output

■ ***A higher ionic conductivity electrolyte would be desirable***

Sodium Super Ion Conductors

“NaSICon”

- $\text{Na}_{1+x}\text{Zr}_2\text{Si}_x\text{P}_{3-x}\text{O}_{12}$
- Extremely high ionic conductivities reported (10^{-3} S/cm) at room temperature
- Limited studies on use in solid-state batteries



90°C data from Breval, *et. al.*, *Brit. Cer. Trans.*, **93** (76), 239-251 (1994)
 300°C data from Goodenough, *et. al.*, *Mater. Res. Bull.*, **11** (2), 203-220 (1976)

NaSiCon Thin Film History (It isn't pretty....)

- Extremely limited literature base
- Virtually no rigorous characterization of material properties
- *Opportunity to make an impact*

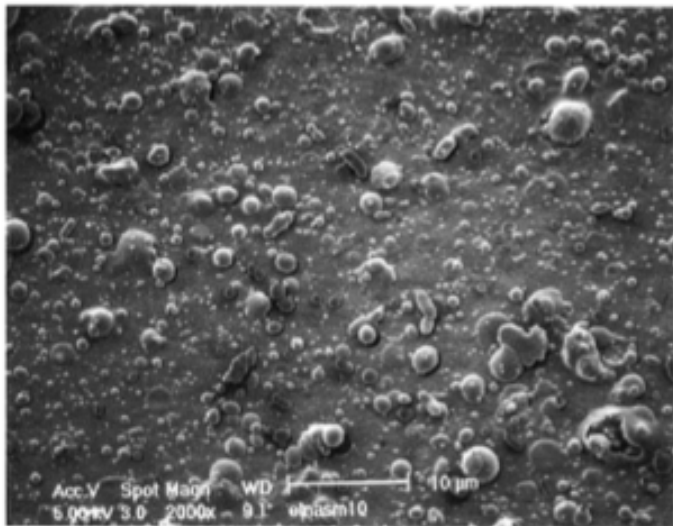


Fig. 2. Micrograph of a NASICON thin film deposited at 1.5 J/cm² on a Raipore membrane.

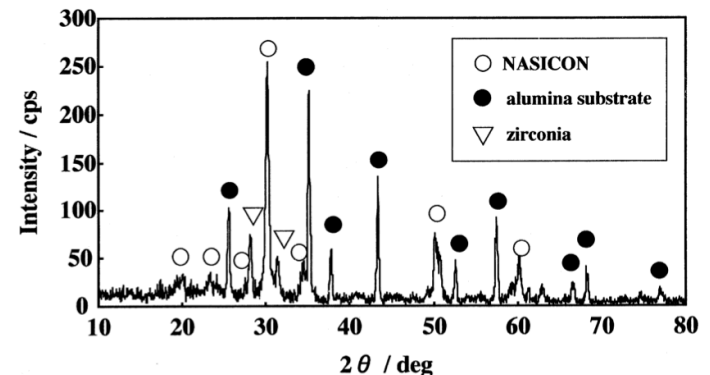
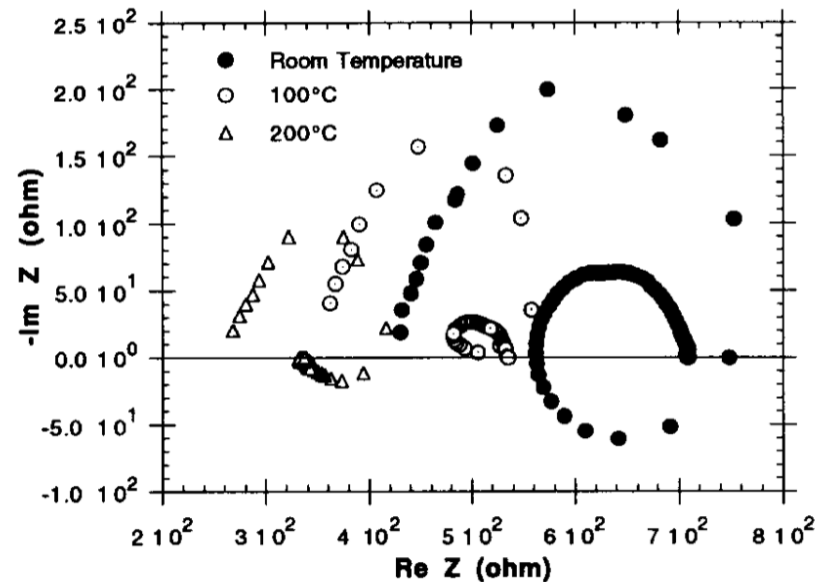
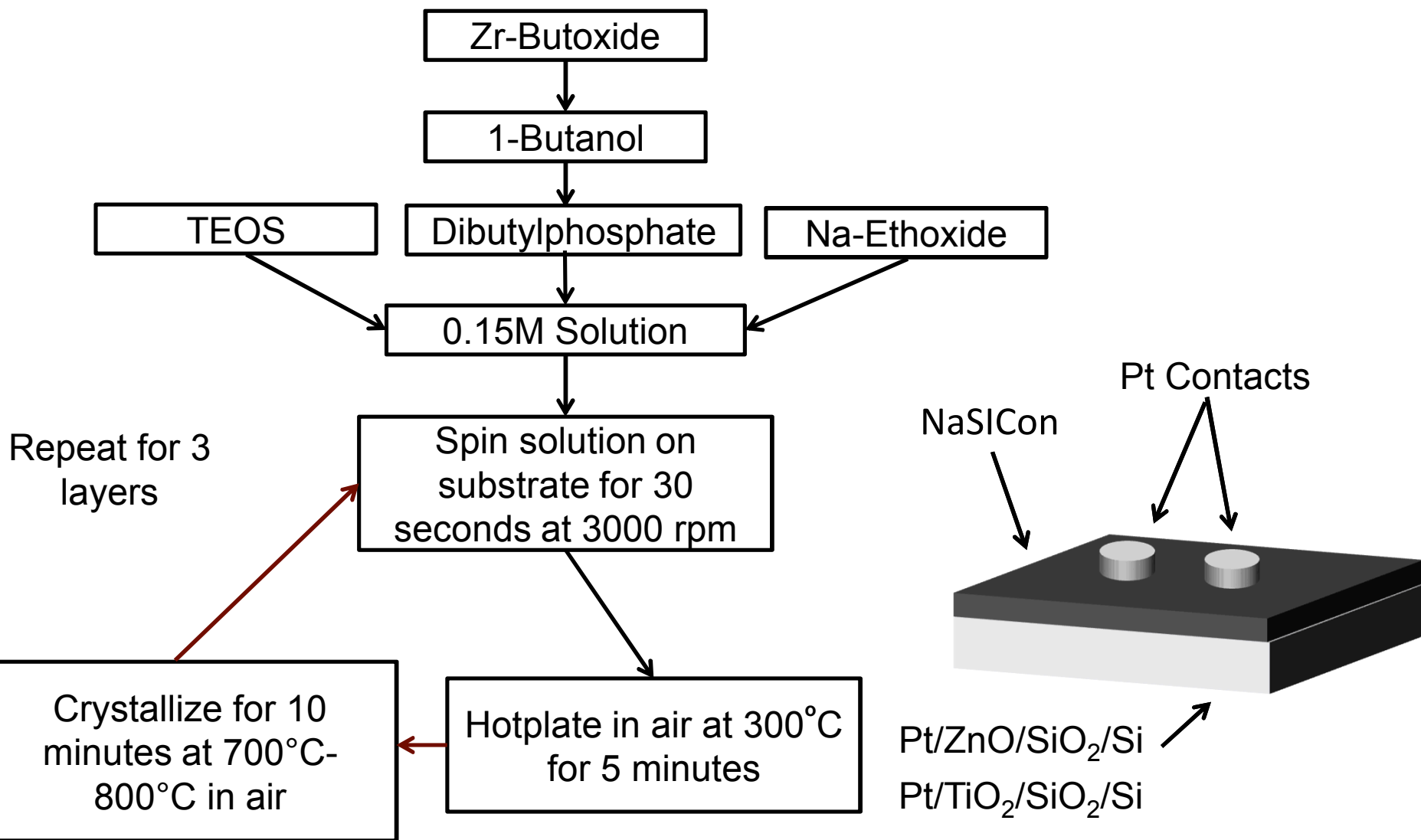


Fig. 7. XRD pattern of the NASICON thin film prepared by spin-coating on an alumina substrate (50 coatings; 1000°C 3 h × 5).

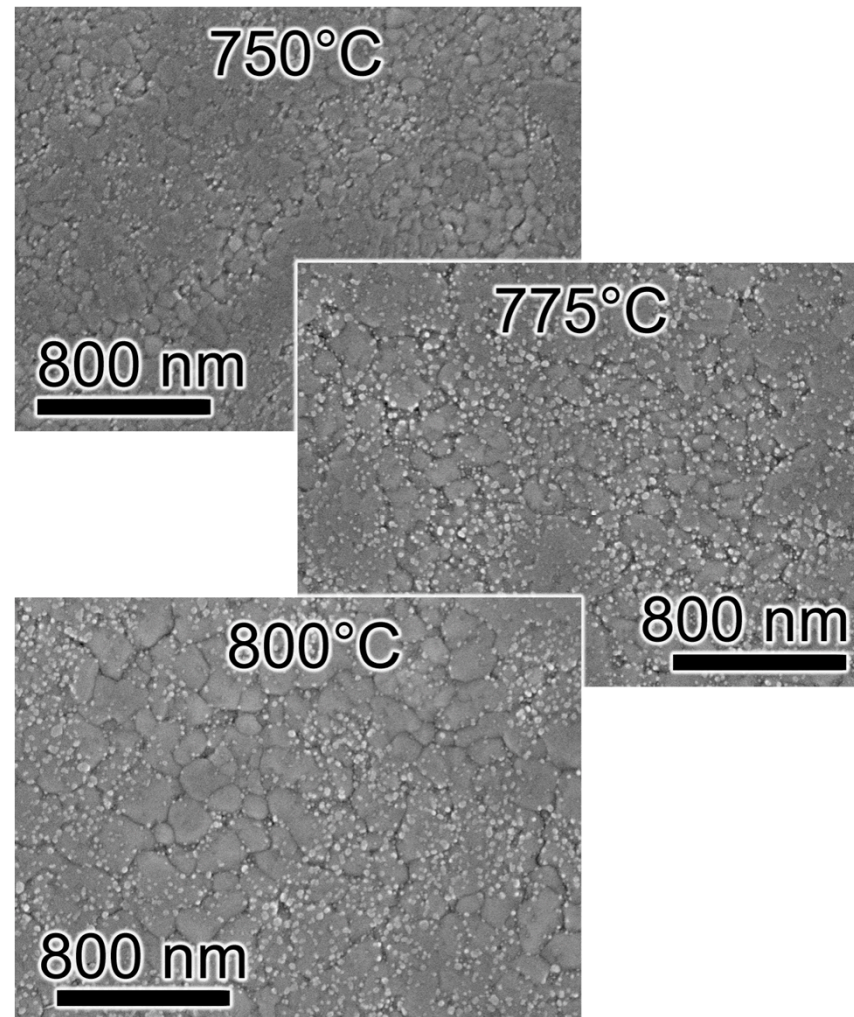
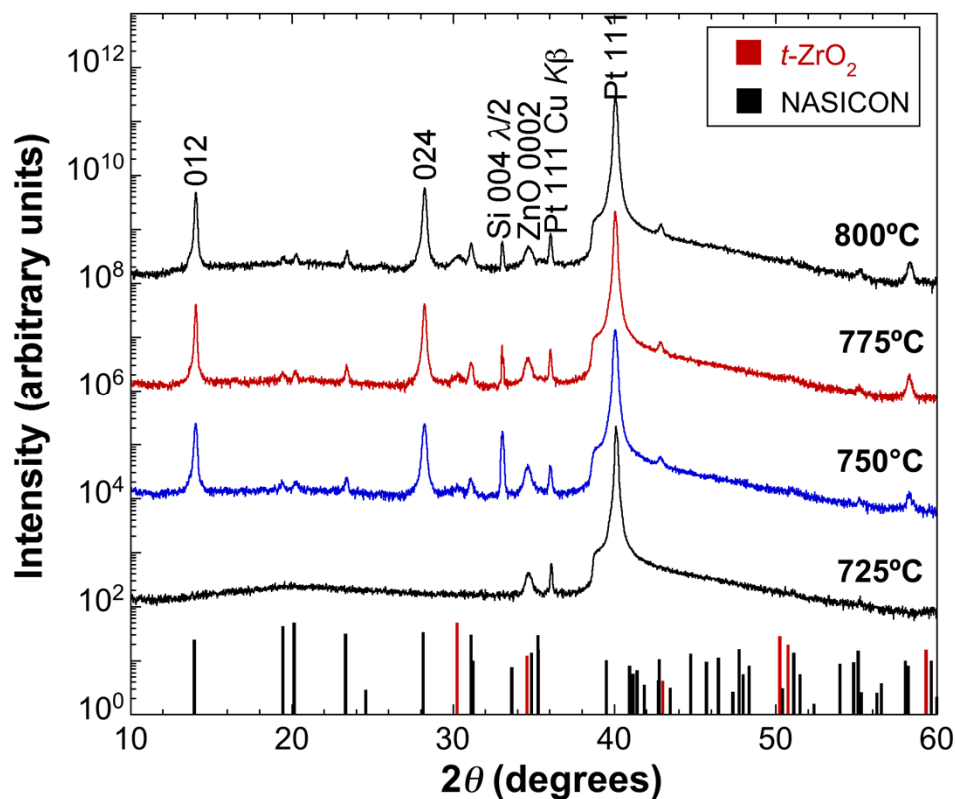
Film Preparation – General Flow



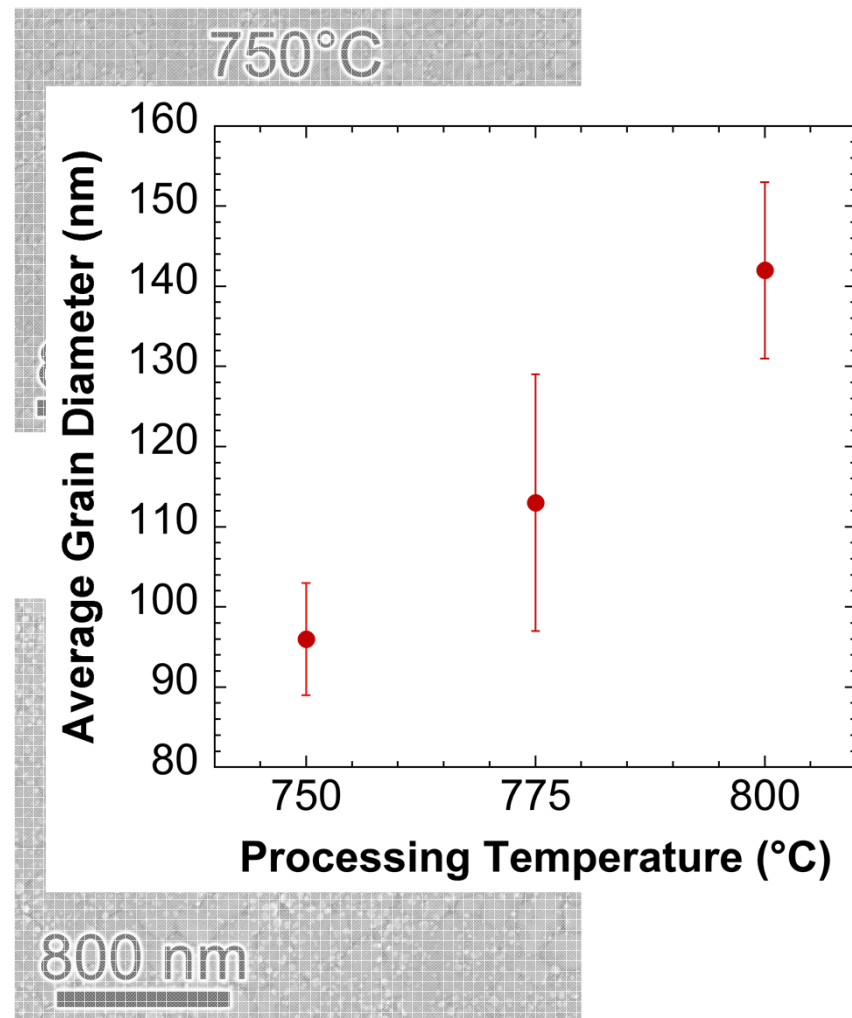
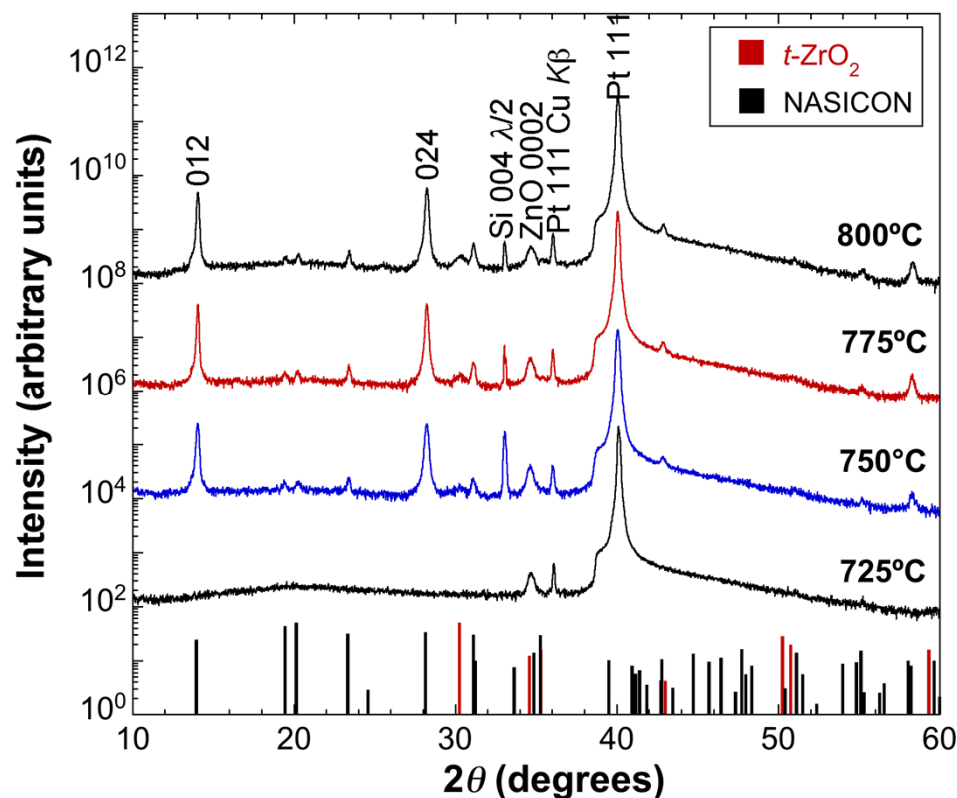
Solution chemistry loosely based upon:

N. Gasmi, *et al.*, J. Sol-gel Sci. and Tech. **4**, 231-237 (1995) and A. Martucci, *et al.* J. Eur. Cer. Soc., **22**, 1995-2000 (2002)

NaZr₂P₃O₁₂ Phase Development and Properties

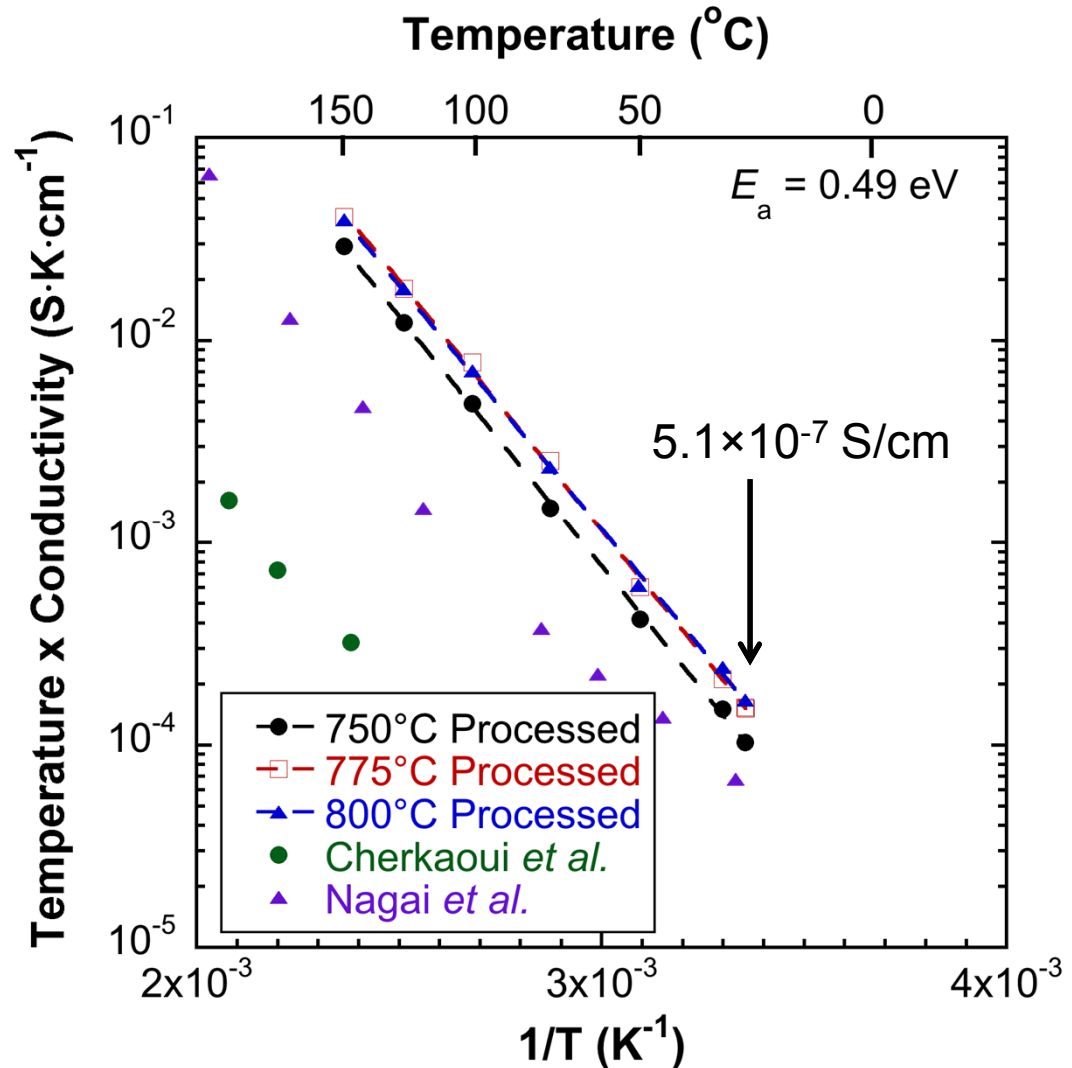


NaZr₂P₃O₁₂ Phase Development and Properties



NaZr₂P₃O₁₂ Ion-Conductivity Behavior

- Temperature dependence assessed
- Activation Energy of ~0.49 eV calculated
 - Invariant with processing temperature
 - Identical to bulk literature
- Conductivity values compare favorably with bulk ceramics
 - Bulk ceramics noticeably lower conductivity – attributed to lower density (85-90% for Nagai)

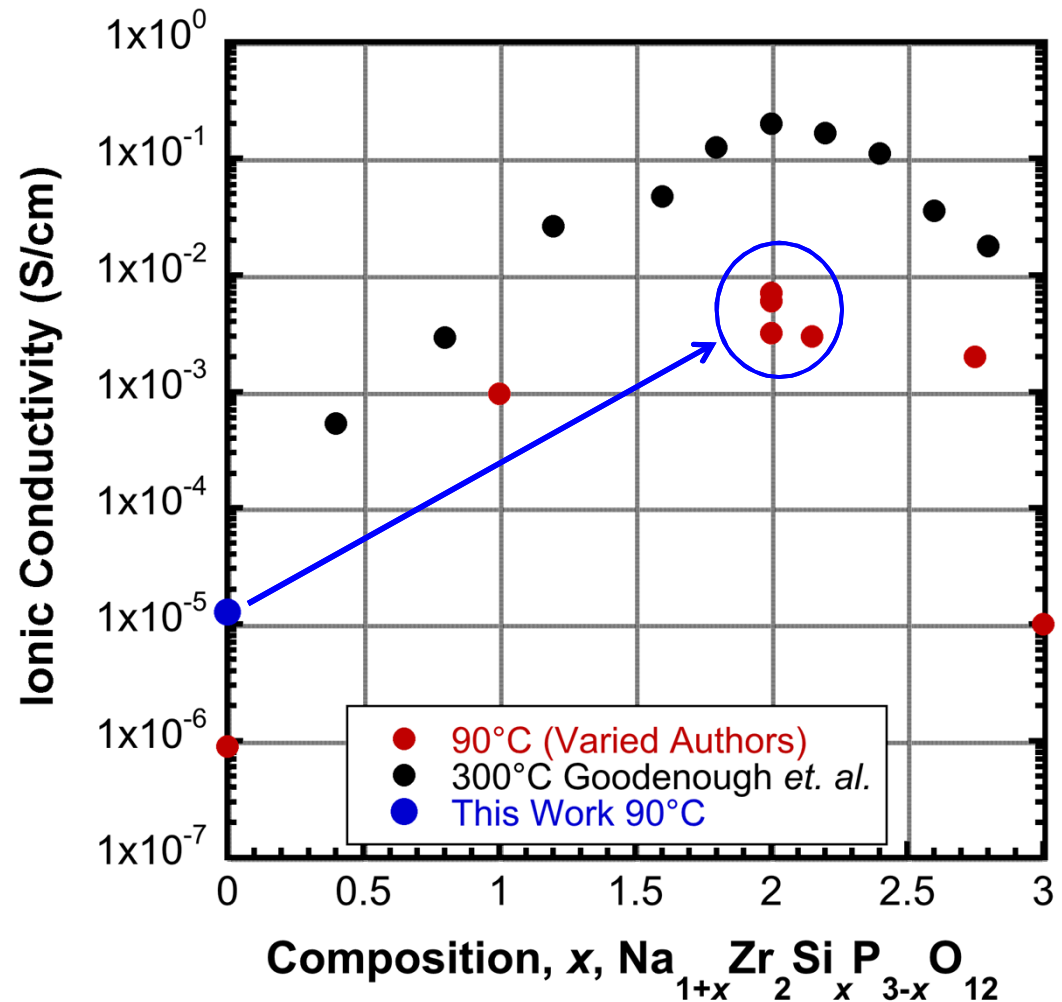


Nagai *et al.*, *J. Amer. Cer. Soc.*, **63** (7-8), 476-477 (1980)

Cherkaoui *et al.*, *Solid State Ionics*, **21** (4), 333-337 (1986)

NaZr₂P₃O₁₂ Ion-Conductivity Behavior

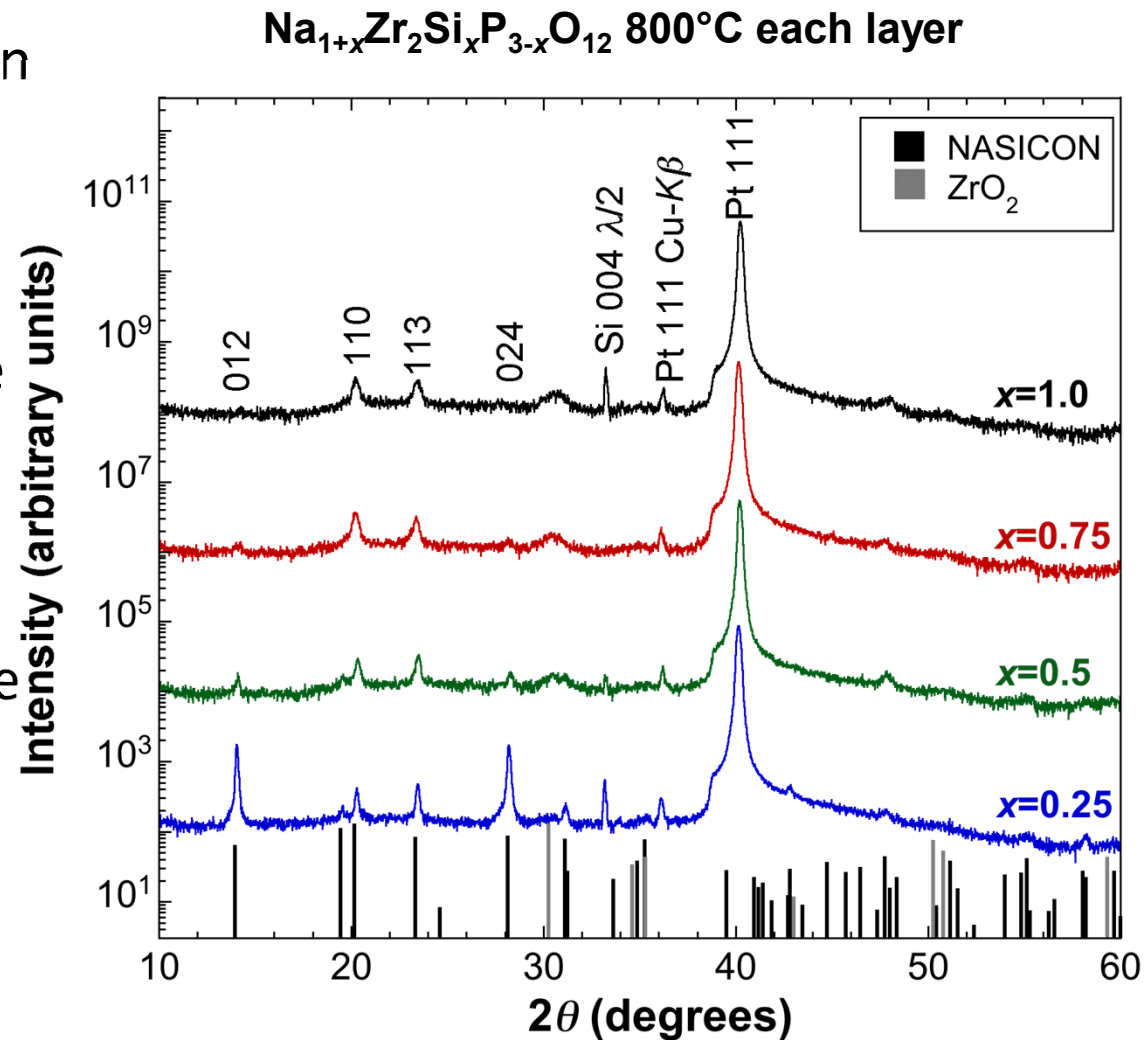
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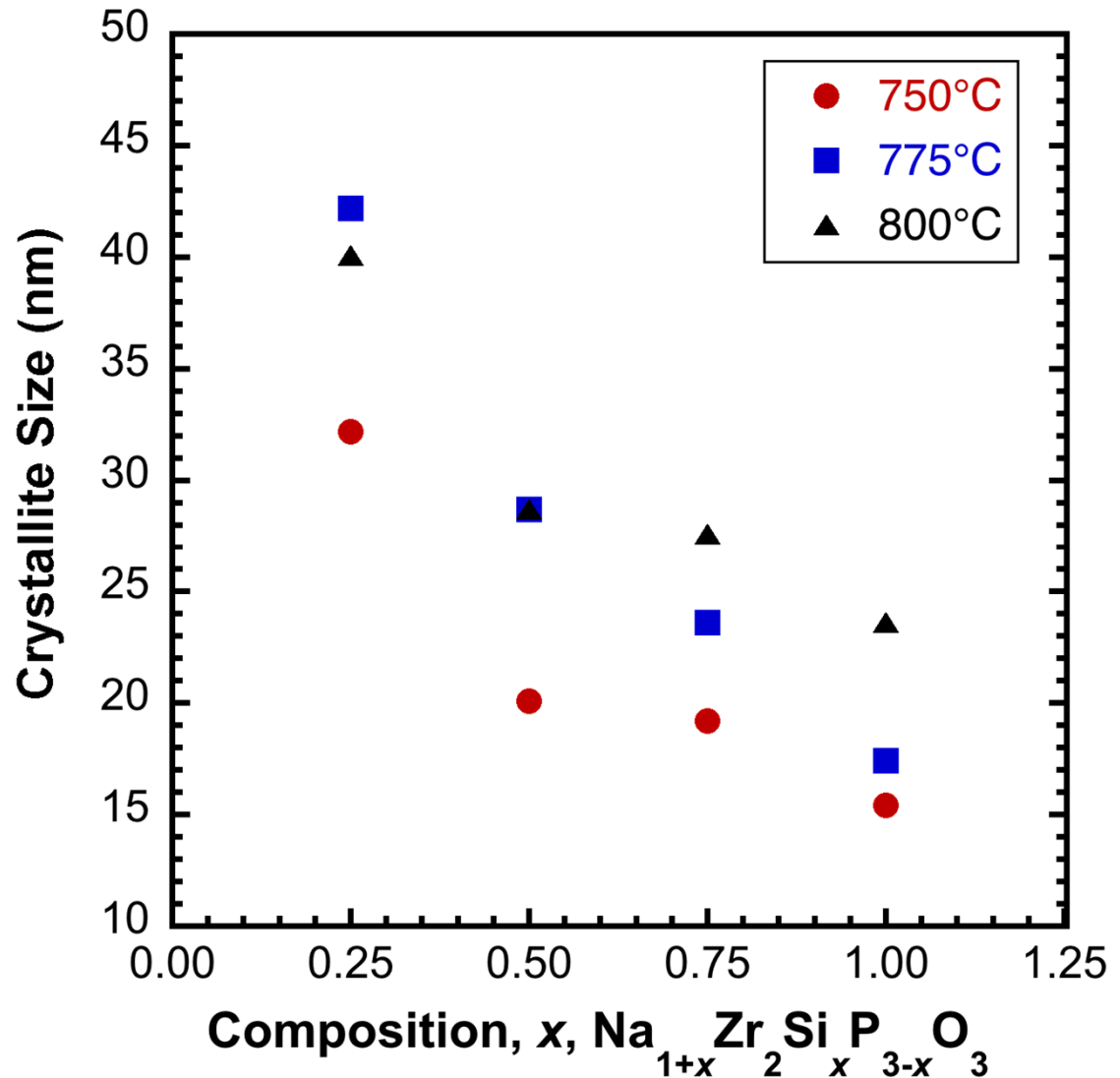
Adding Silicon to the Mix....

- Preferred texture goes away with increasing silicon content
 - Change in nucleation mechanism?
- X-ray peak widths increase with silicon content
 - Suggests reduced crystallite/grain size
- X-ray peak widths decrease with process temperature
- Possible increase in ZrO_2 peak intensity



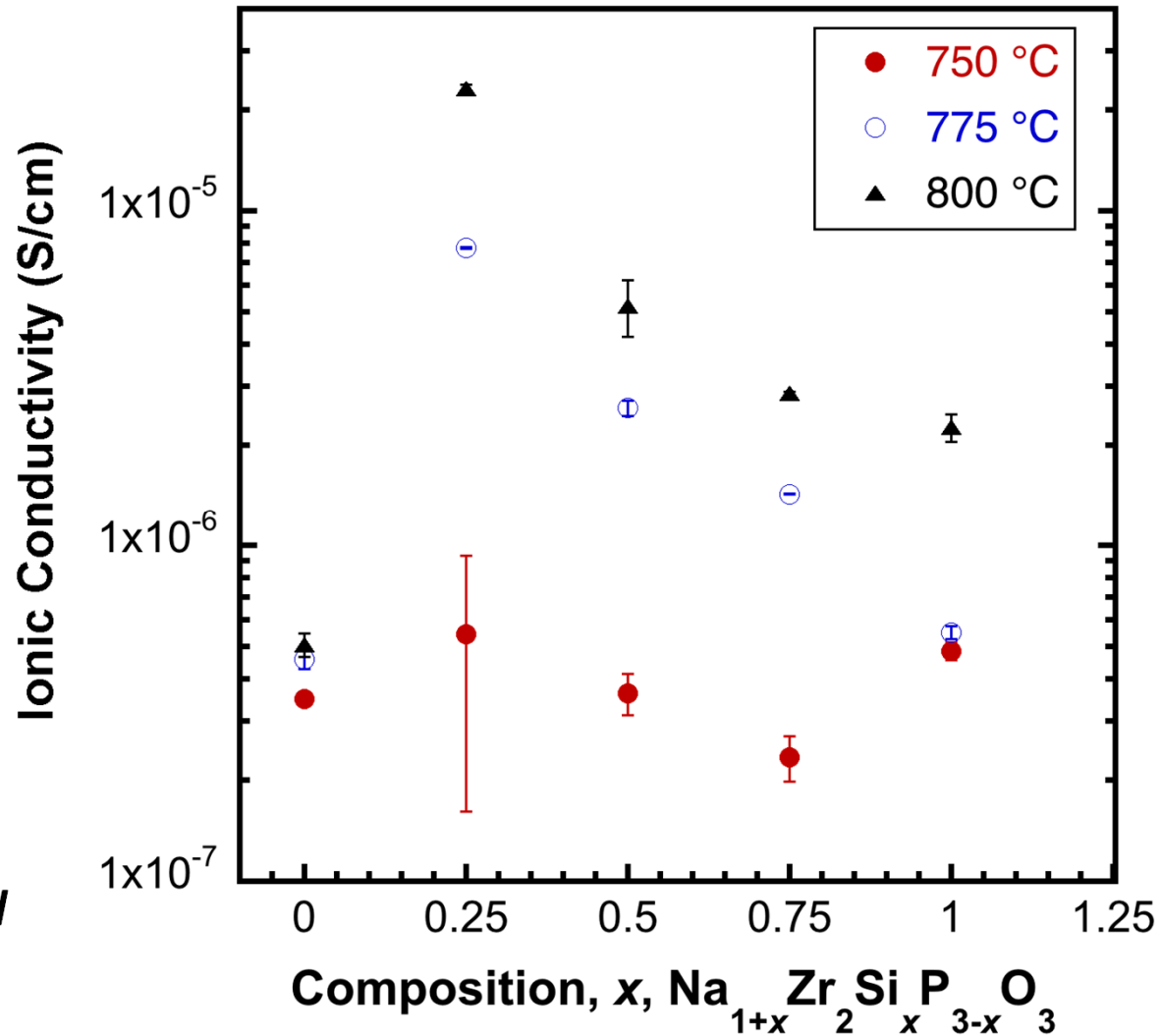
Crystallite size scales with silicon content

- Crystallite size determined from 110 peak FWHM (Scherrer's Formula)
- Crystallite size decreases with increasing silicon content
 - More refractory?
- Crystallite size decreases with decreasing processing temperature



Ionic conductivity scales with silicon content

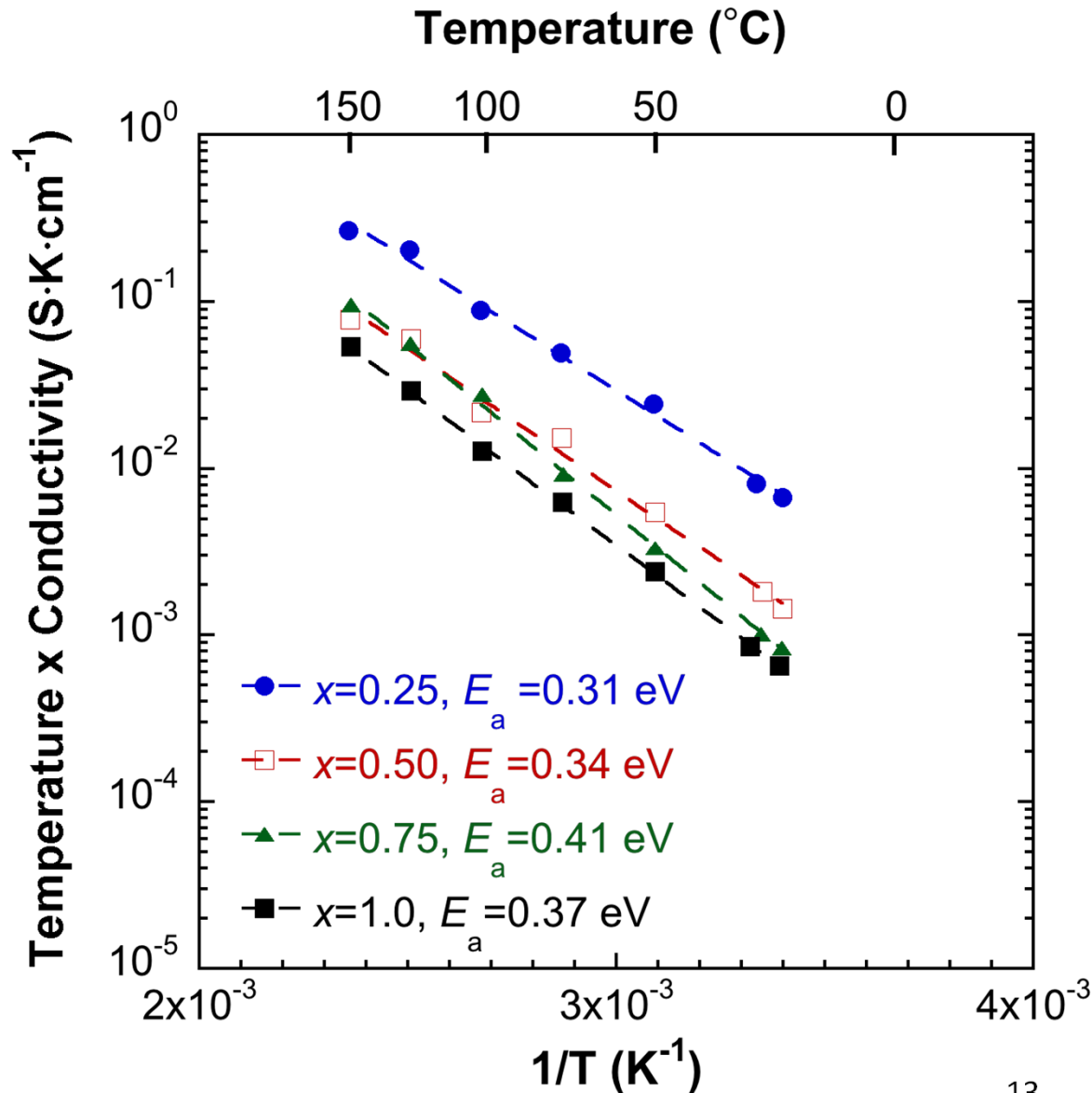
- Increase in ionic conductivity at $x=0.25$
- Decrease in ionic conductivity with $x>0.25$
 - *Different than expected bulk response*
- Increased ionic conductivity with increase process temperature for each composition
 - *Consistent with increased crystallite size*



Ionic conductivity scales with silicon

content

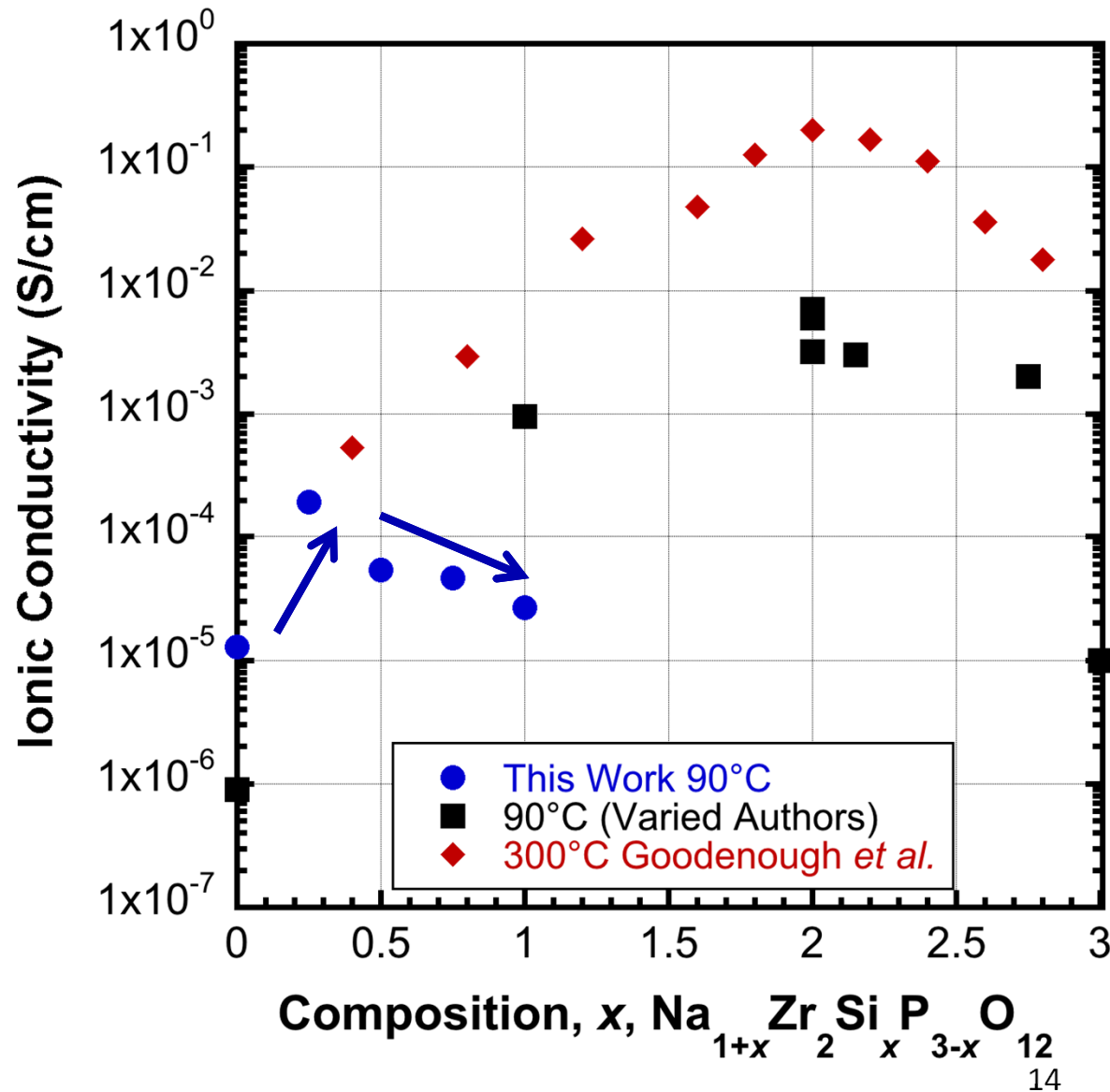
- Maximum ionic conductivity for $x=0.25$ composition
- Activation energies for ionic conduction consistent with bulk values for same compositions
 - $x > 0.25$ films *act* like bulk conductors, but have depressed values
- ***Decreasing crystalline perfection appears to dominate response***



Ionic conductivity scales with silicon

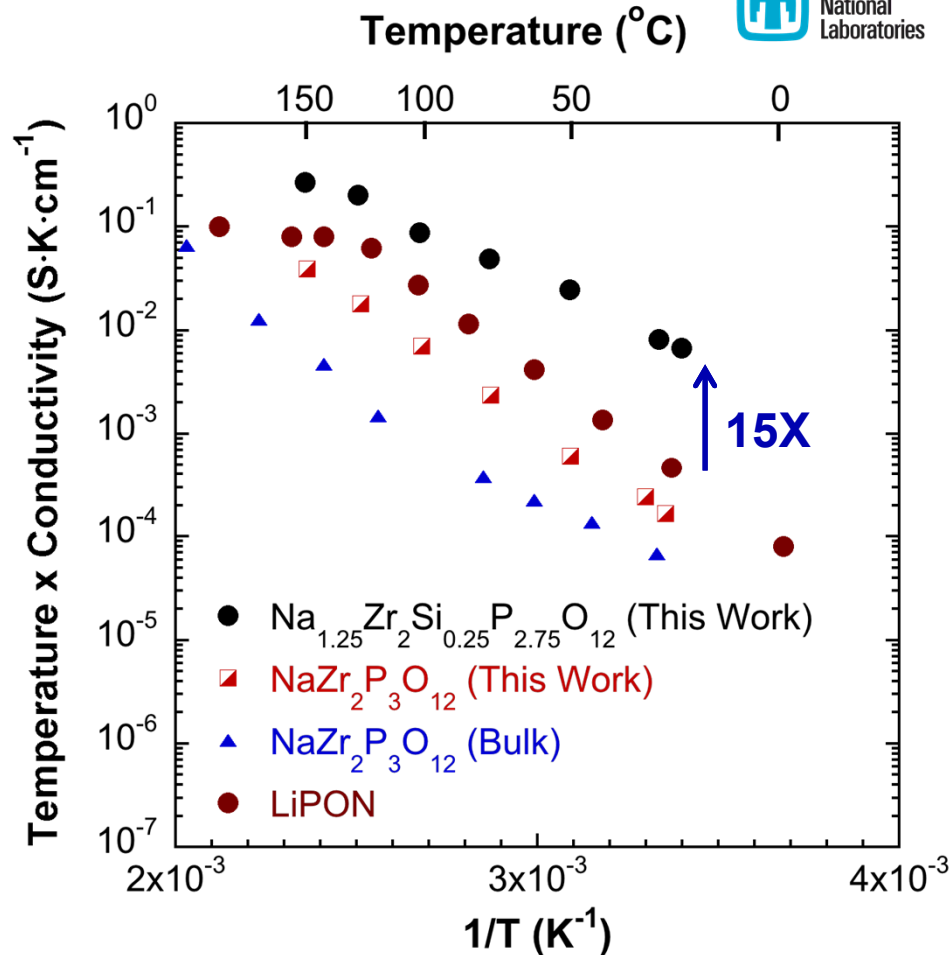
content

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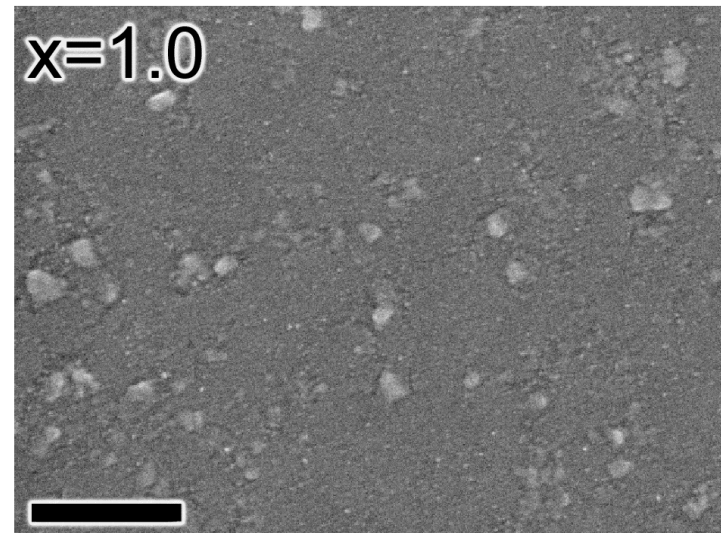
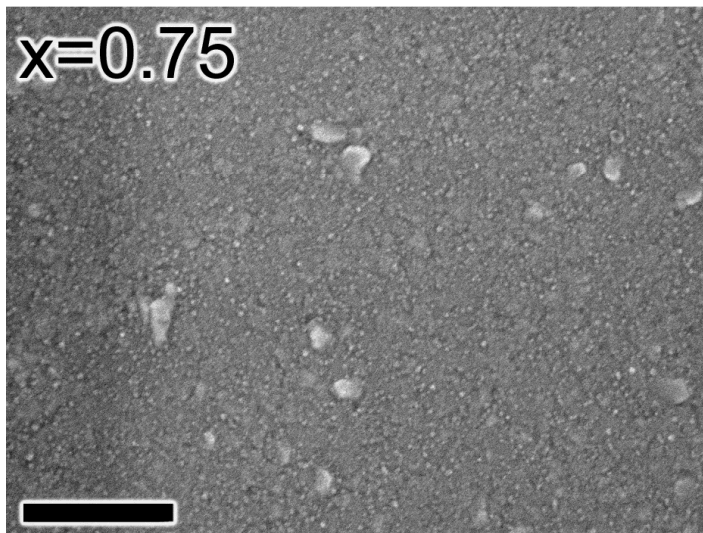
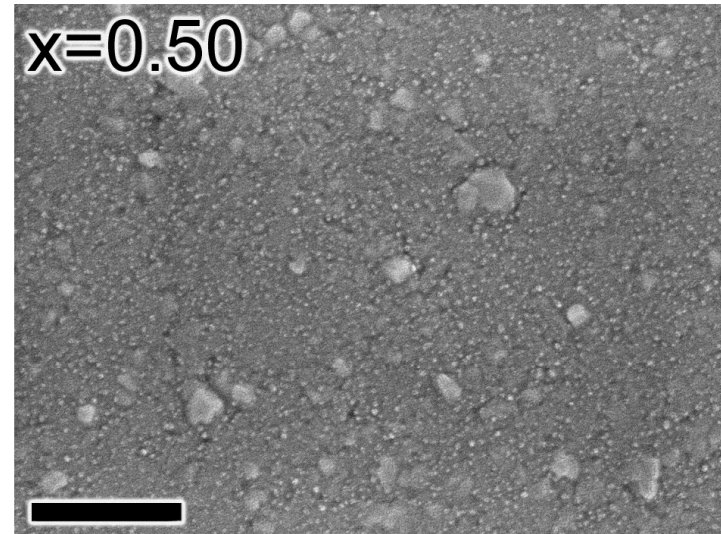
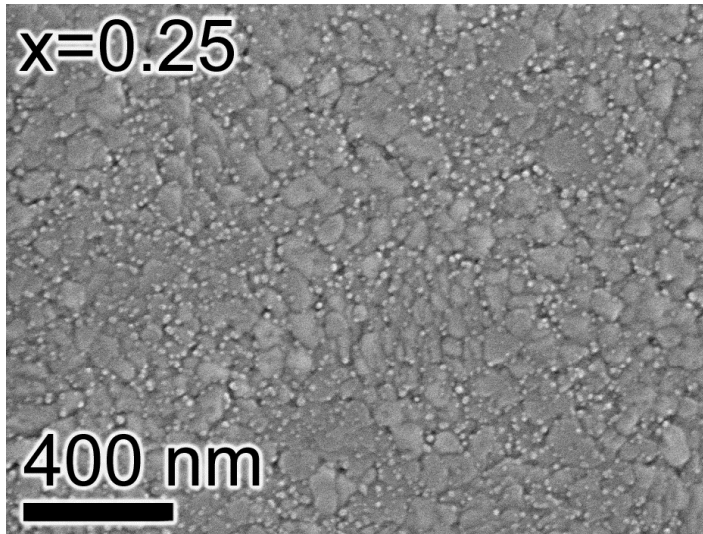
Summary

- NaSICon thin films can be prepared via a simple chemical solution technique (up to $x=1$)
- *NaSICon films can have ion conductivities higher than bulk counterparts*
 - *Likely due to improved density*
- Addition of silicon to $x=0.25$ results in an $60 \times$ conductivity increase
- Additional silicon substitution results in decreased conductivity
 - Poor crystallinity
 - Fine grain size



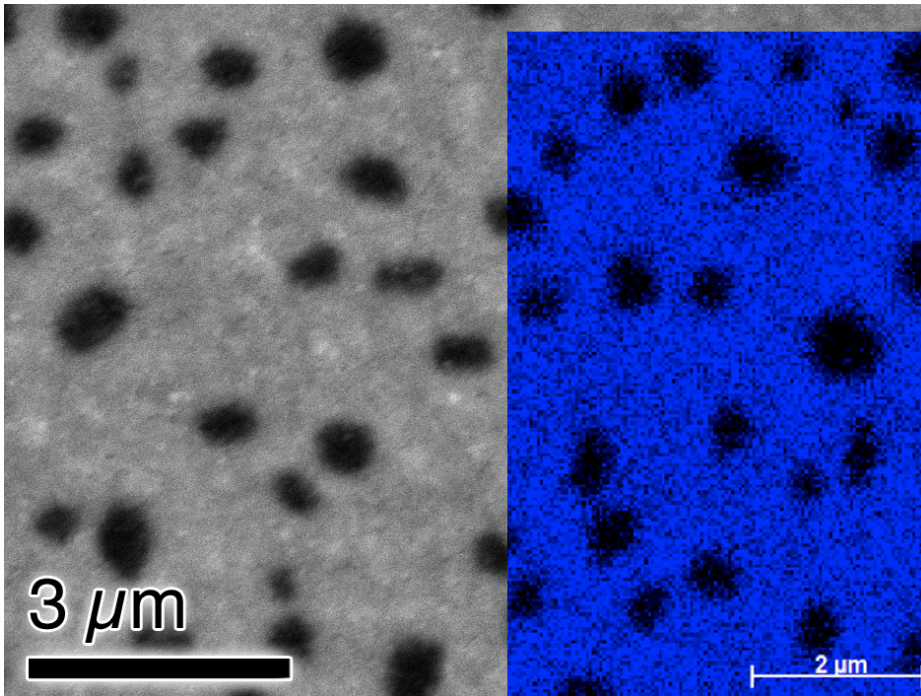
- *Solid state Na-ion batteries are a promising alternative to lithium particularly for high power applications*

Microstructure Changes with Composition



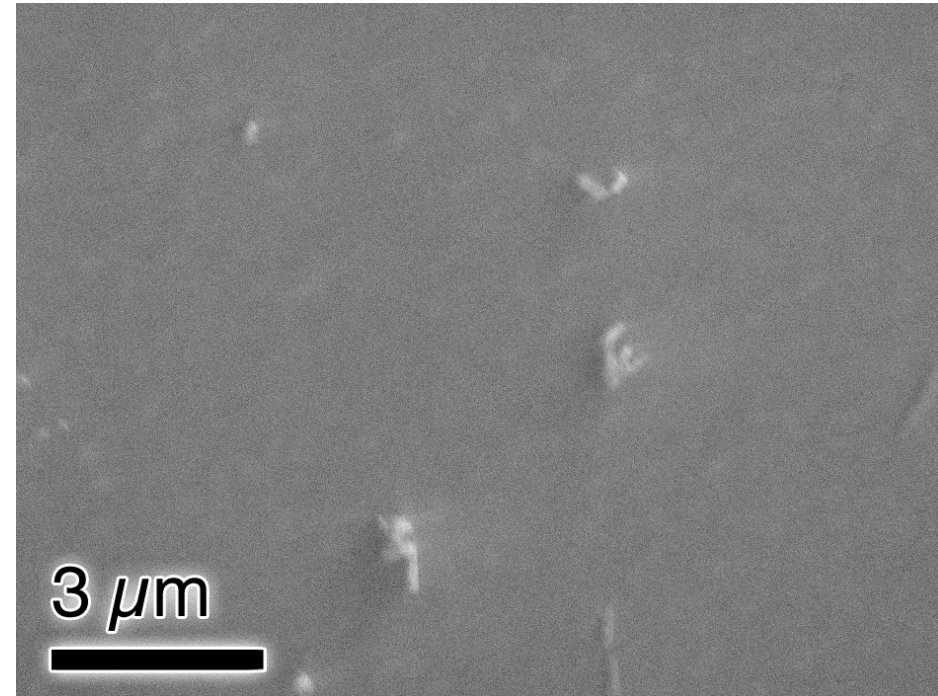
Why not go hotter? *Electrode* *Instability*

$x=1$ NaSiCon on
Pt/ZnO/SiO₂/Si after 800°C



SE2 at 15 kV
Holes in the Pt Layer
(Reaction with Na)

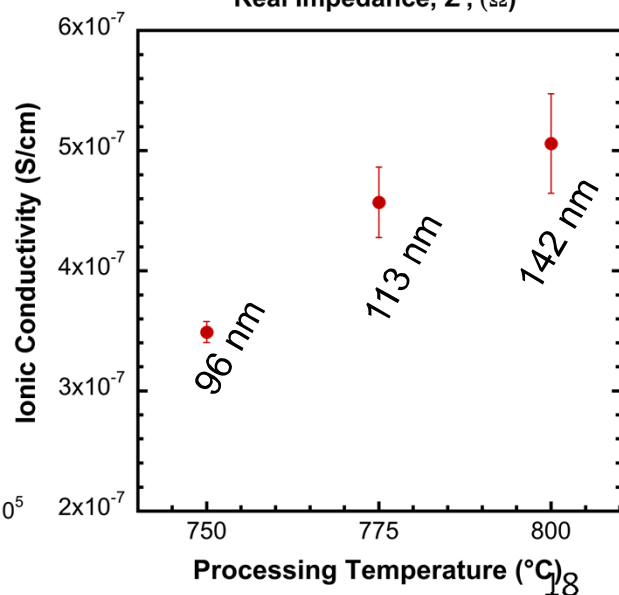
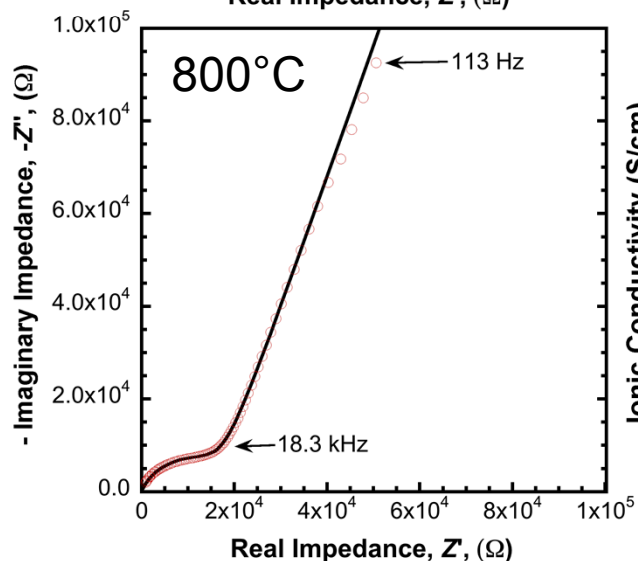
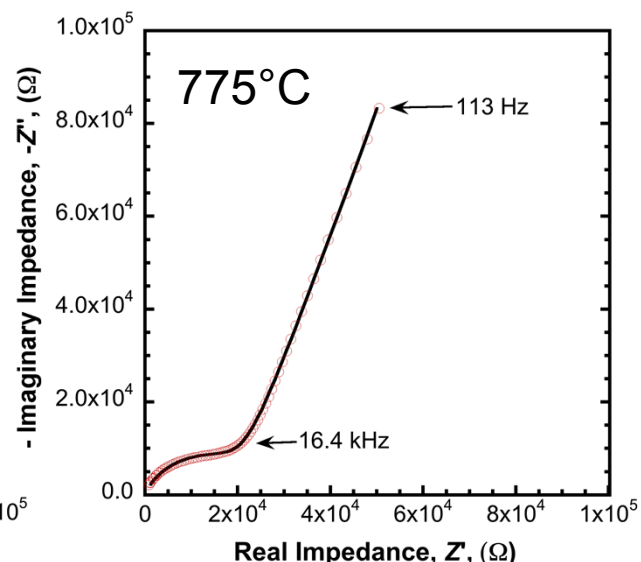
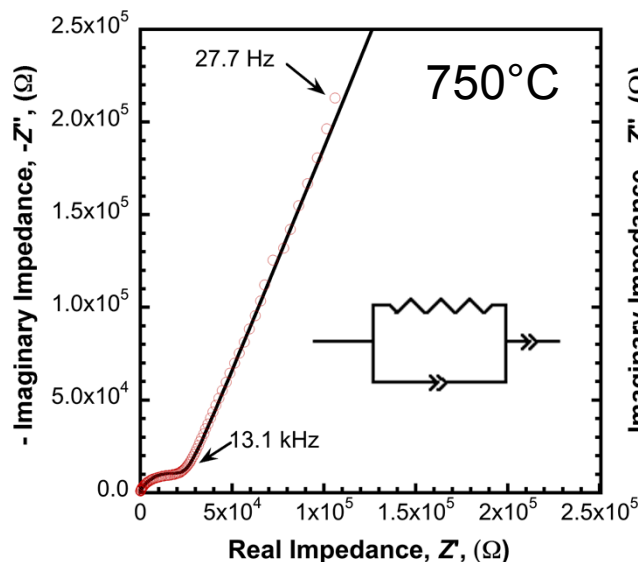
$x=1$ NaSiCon on
Pt/TiO_x/SiO₂/Si after 800°C



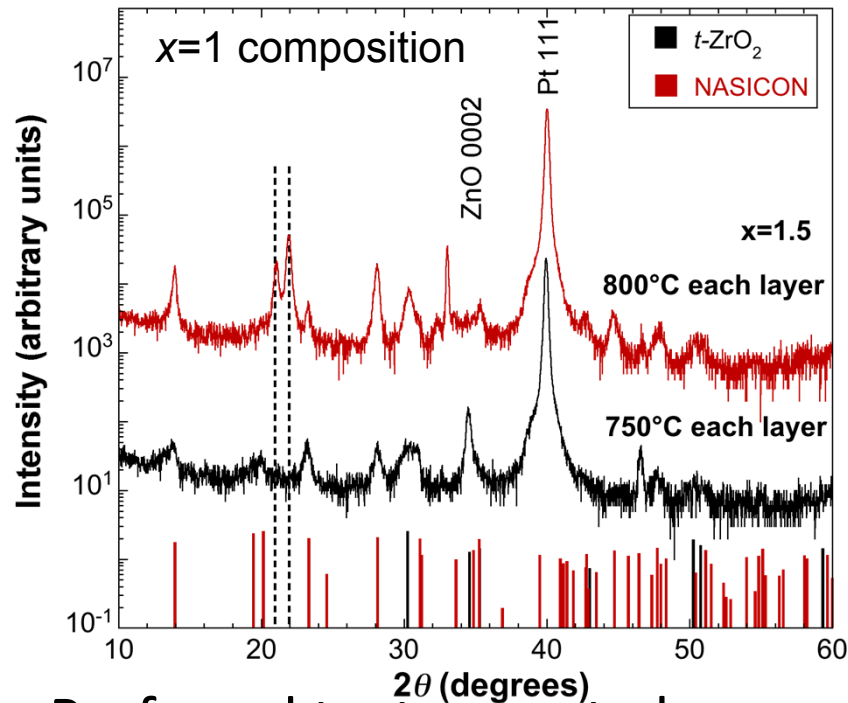
SE2 at 20 kV
No Holes in the Pt Layer
(Interdiffused Ti May Pin Pt)

NaZr₂P₃O₁₂ Impedance Response

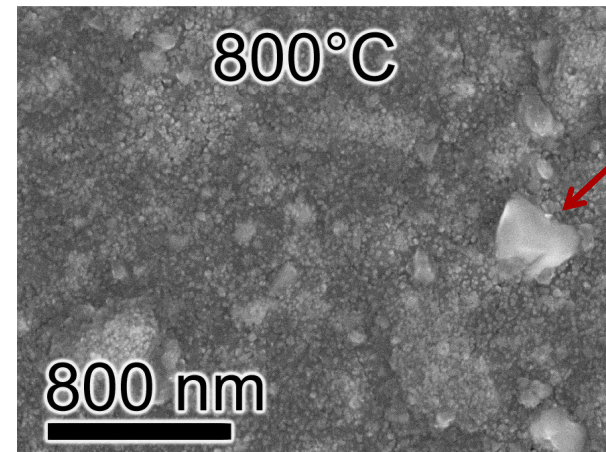
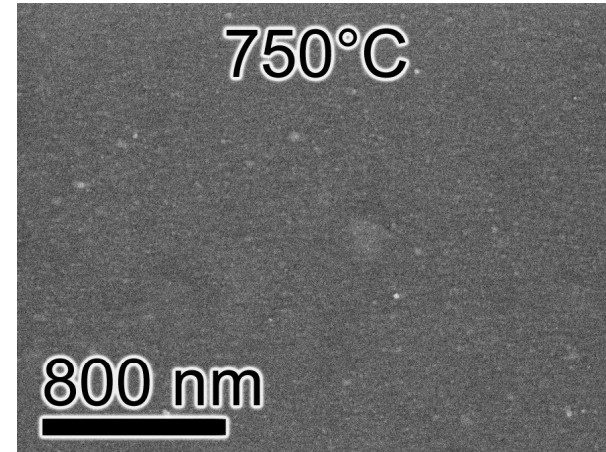
- Pt/NZP/Pt structures prepared
- Ion-blocking behavior confirmed for each film
- Ion conductivities calculated from resistive element
- Clear trend of increasing conductivity with grain size



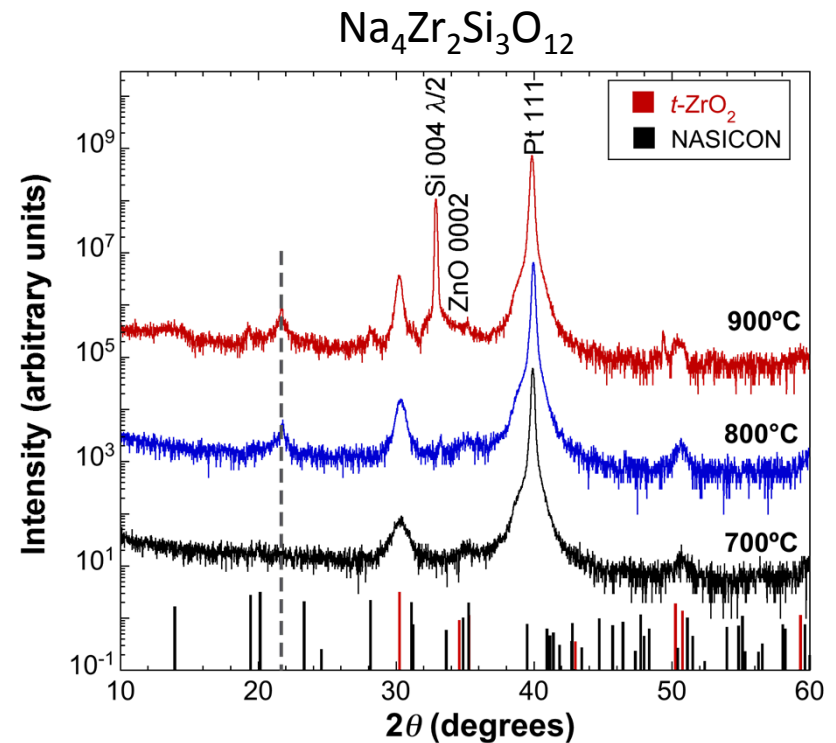
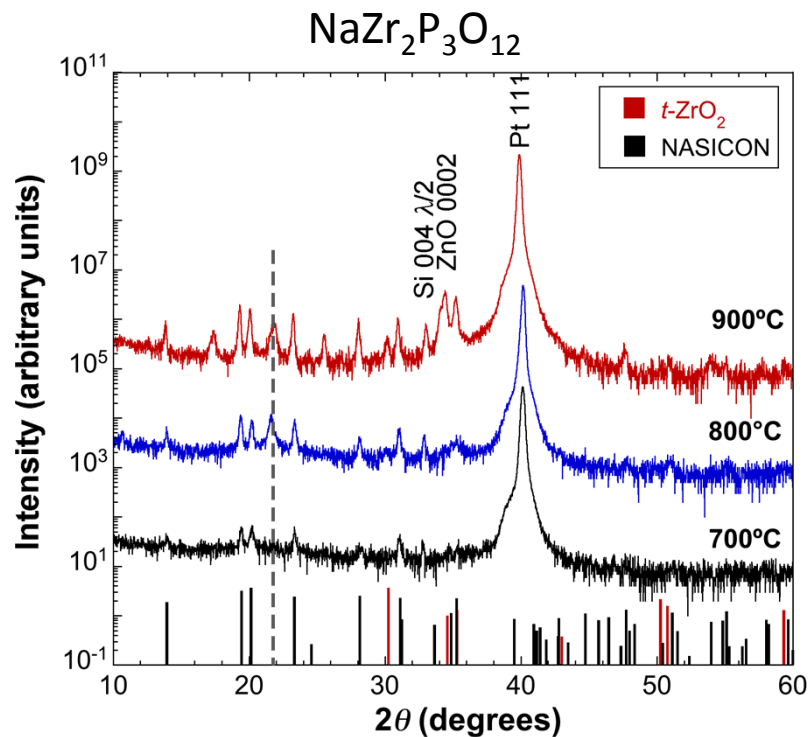
Adding Silicon to the Mix....



- Preferred texture not observed
- ZrO_2 secondary phase becomes more prominent
- Grain size drastically reduced
- *Heating to higher temperatures results in secondary phase*



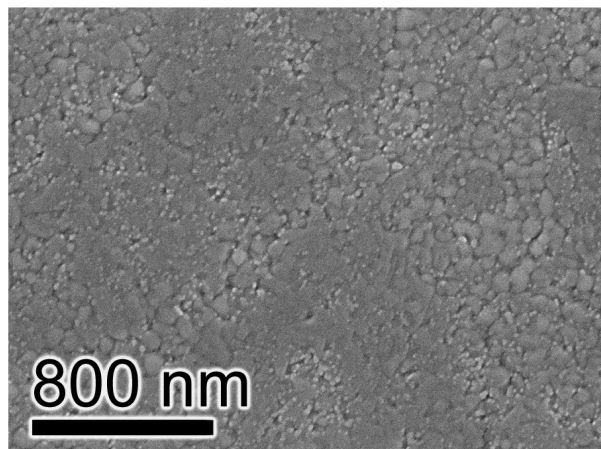
Phase Development: Initial Observations



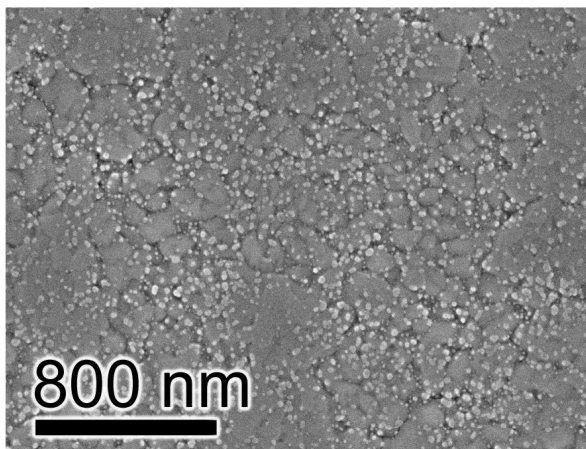
- Every layer fired to 700° C x 10 minutes, 30 minute post anneal at designated temperatures
- Can unambiguously identify NaSiCon peaks in NZP films
- Silicon end-member is comprised of ZrO_2 and an unknown phase

Rigorous Study of $\text{NaZr}_2\text{P}_3\text{O}_{12}$ Phase Development and Properties

750°C



775°C



800°C

